# HYCON HYCON TECHNOLOGY 

## HY11P13 <br> Application Note <br> 3000 Counts Pricing Scale

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## 1. Brief Introduction

Not only the characteristics of peripheral components should meet the requirements but also the measurement IC must achieve the specification due to pricing scale needs to be strictly certified, including temperature, precision, resolution and anti-interference capability (ESD \& EMI) was requested as well. Therefore, simplifying peripheral passive components (resistors) could reduce temperature impact on measuring. It is more cost saving and has significant improvement of anti-interference ability.

## 2. Theory

### 2.1 Sensor Components

The theory of load cell is to stick strain gauge, which is made of bridge resistors on the aluminum pan. It is the so called "strain gauge".


Strain gauge resistance generates $\Delta \mathrm{R}$ change value when the aluminum pan was distorted from the pressure.


The $\Delta R$ change value that generated from the two signal sides is:

$$
\begin{aligned}
& \mathrm{V}_{+}-\mathrm{V}-=\left(\frac{(\mathrm{R}+\Delta \mathrm{R})}{(\mathrm{R}-\Delta \mathrm{R})+(\mathrm{R}+\Delta \mathrm{R})} \times\left(\mathrm{V}_{\text {IN }+}-\mathrm{V}_{\text {IN }}\right)\right)-\left(\frac{(\mathrm{R}-\Delta \mathrm{R})}{(\mathrm{R}-\Delta \mathrm{R})+(\mathrm{R}+\Delta \mathrm{R})} \times\left(\mathrm{V}_{\text {IN }+}-\mathrm{V}_{\text {IN }}\right)\right) \\
& \mathrm{V}_{+}-\mathrm{V}-=\frac{\Delta \mathrm{R}}{\mathrm{R}} \times\left(\mathrm{V}_{\text {IN }+}-\mathrm{V}_{\text {IN }}\right)
\end{aligned}
$$

A/D transformed the physical signals to digital signal and the results are shown on the display. The voltage change is approximately the same scale of mV voltage signal (due to $\Delta \mathrm{R}$ change value is less than R ). In order to realize a high precision scale, the ability to process 0.1 uV signal is very necessary. On the contrary, if ADC performance is not good enough to achieve the target (noise processing), voltage signal must be amplified through OP so as to meet the precision requirement.

The factors are more complicated after OP amplifier. Not only OP capability should satisfy the request but the peripheral resistors must achieve the requirement of
temperature change as well. The total cost will be relatively high under this kind of solution (through OP amplifier). Therefore, the accuracy of ADC is indeed critical and is the key element. If the signal that outputted from Load Cell must be transformed to digital signal, high resolution ADC, equipping with the ability to process 0.1 uV signal, is in need. Only this way, a qualified scale can be accomplished.

Load Cell resistance of pricing scales is around $1 \mathrm{~K} \Omega$ and $\Delta R$ change value is only $1 \Omega$ maximally. Suppose the voltage of VIN+-VIN- is 3 V , the output signal VIN+-VIN- is only 3 mV . To realize kitchen scales of 3000 Count and internal/external resolution is 1:10, the minimum signal value should $\frac{3 m V}{3000 \times 10}=0.1 \mathrm{uV}$

Determining whether ADC performance could achieve the specification depends on how to control and stabilize the resolution by RMS Noise. The internal resolution which people presumed by visual interpretation was usually one count rolling after the software processing. The full-scale represents the internal resolution and the signal of one count was on behalf of 2~3 times RMS Noise. With regards to the pricing scales which need to be certificated, the internal/external resolution ratio should reach 1:10 at least. As for the electrical scales without certification, in order to have the perfect performance, will try to improve the external resolution as much as possible and reduce the ratio of internal/external resolution. However, it is not easy to stabilize external value by regular software processing when the ratio is less than 1:3.

For developing electrical scales, the bottleneck of how to achieve the utmost internal resolution by the series of HY11PXX is not ADC resolution but Input RMS Noise. At the configuration of PGA=8, ADC Gain=16, OSR=32768, the Input RMS Noise is around 100 nV while 8 datum out per second. Due to Input Noise of the series of HY11PXX is composed of thermal noise; we can further reduce the noise through average software method. (Other IC P/N's Input Noise is composed of Flick Noise. It cannot be reduced by average software.) According to our detailed experiment findings, if we averaged 8 datum, the Input RMS Noise could be decreased to 40 nV . Moreover, if 16 data is averaged, the noise could be further reduced to 30 nV , but it took 2 seconds at least to be stabled. In other words, averaging 16 datum took more time to stabilize the resolution.

Therefore, if we average 8 datum with the software, the Input RMS Noise is around 40 nV . 3 times RMS Noise represents one count rolling(= 120 nV ). The full-scale $1 \mathrm{mV} / \mathrm{V}$ Load Cell can reach 2.4 mV when using Load Cell driving voltage of 2.4 V . Under this circumstance, the internal resolution would have 20000 Counts.

### 2.2 Control IC

### 2.2.1 11P13 ADC Features

- Low Operating Voltage
- ADC Gain $\rightarrow$ ADC minimum operating voltage:2.4V
- Build-In Programmable Gain Amplifier (PGA) $\rightarrow \times 1 / 4 \sim \times 16$

$$
\rightarrow \times 1 \sim \times 8
$$

- Reference Voltage Configure $\rightarrow \times 1 / 2 \& \times 1$
- Offset Configure $\rightarrow 0, \pm 1 / 4$ Vref $, \pm 1 / 2 \mathrm{Vref}, \pm 3 / 4 \mathrm{Vref}$
- Build-In Input Signal Switch $\rightarrow \mathrm{V}+\mathrm{V}-\mathrm{V}+$ short, V - short , V+ V- cross, 4 Switch Modules
- Multi-Channel Input Signal
- Various Output Rate Selection $\rightarrow$ ADCK / 256 ~ ADCK / 32768
- High Resolution $\rightarrow$ 18-bit Output resolution
- Minimum Resolution Voltage $\rightarrow$ Minimum resolution voltage: 0.07 uV
- Rail to Rail Signal Output $\quad \rightarrow$ Minimum Input Signal: VSS - 0.2V, Maximum: VDDA
- Gain Low Temperature

Drift Parameter $\quad \rightarrow 10 \mathrm{PPM} /{ }^{\circ} \mathrm{C}$

### 2.2.2 11P13 IC Features

- Various System Oscillation Frequency Selection $\rightarrow$ Internal 32K, 2MHz, external 32K ~ 16MHz
- Low Power
- Build-in LCD Driver
- Low Voltage Detect
- Build-in multi-steps regulated output
- SPI communication
- PWM/PDM output
$\rightarrow$ Turn On ADC by internal 2 MHz . Maximum power consumption<1mA
$\rightarrow 4 \times 20$ display
$\rightarrow$ Multi-Step Power Voltage Detection

$$
\rightarrow 3.3 \mathrm{~V}, 2.93 \mathrm{~V}, 2.64 \mathrm{~V}, 2.4 \mathrm{~V}
$$

## 3. Design Scheme

### 3.1 Hardware Illustration



Figure 1

The whole circuit can be divided into 3 parts :

- ADC
- Low Voltage Detect Circuit
- Power and Peripheral Circuit


### 3.1.1 ADC



Figure 2
Output voltage of Load Cell was provided by 3.3V regulator. This voltage enables Load Cell to $2 \mathrm{mV} / \mathrm{V}$ to have maximum output signal, 6.6 mV . ADC internal PGA and Gain is configured as 8 -amplification. If VRGN equals to 1 (VREF $\times 1 / 2$ ), it could fulfill the minimum resolution requirement, 0.02 uV when ADC outputs $\pm 15$ bit. Since HY11P13 equips with good temperature characteristics and its general temperature curve is around $\pm 10 \mathrm{ppm}$, it only takes $2 \sim 3$ low temperature drift resistances and Load Cell to accomplish the pricing scale certification request. When the temperature was changing, to make sure ADC had enough operating time, it's necessary and proposed to connect capacitors which were located at AI0-AI1\& AI2-AI3.

### 3.1.2 Low Voltage Detect Circuit

Since VDD power output through the regulator, it is impossible to use VDD to implements low voltage detect. Battery voltage needs to be divided and input through SVSIN of HY11P13 internal power managing system. Battery voltage was divided to SVSIN through R1 \& R2 while PT2.5 output high. SVSOP of HY11P13 power managing system would show 1 if SVSIN voltage lowers than 1.2 V so that is can judge whether battery voltage is too low. Owning to the low temperature drift characteristic that HY11P13 internal ACM possessed; it is recommended to adopt low temperature coefficient R1 \& R2 resistors so as to carry out precise low voltage judgment.


Figure 3

### 3.1.3 Power and Peripheral Circuit

Battery power was provided to VDD of HY11P13 through 3.3V regulator. Due to IC power consumption at Sleep Mode was less than 1uA, the power consumption of the whole system depended on the consumption of 3.3 V regulator.


Figure 4
Output voltage of 5V regulator supported Load Cell and reference voltage.

### 3.2 Software Process

### 3.2.1 Increasing ADC Output Bit by Software Average

Since the small signal is amplified to 128 times, ADC output bit can reach $\pm 15$ bit. However, ADC resolution can increase 1~2 bit by software average method. Adding another 7 ADC buffer values to ADC new value and then divided it by 8 . The value will be placed to ADC OUT (See Figure 4). This purpose of average 8 data is to scatter noise and increase the ADC output bit.


Figure 5
Once ADC new value is received, move it to Buffer 1, Buffer 1 to Buffer 2..., Buffer 6 to Buffer 7, as shown in Figure 6


Figure 6

Due to the fact that reflection time of data average is slow, as indicated in Figure 4, it is necessary to skip this program when the process (see Figure 5) brings the greater ADC value. If ADC new value is greater than $0 \times 200$, just record it and it is needless to do any further operation. However, the next value is still greater than $0 \times 200$; it will substitute all of the ADC buffer values. On the contrary, once the next value is not over $0 \times 200$, the process of data average shall continue.


Figure 7

## 4. Technical Specification

### 4.1 Test Result of Temperature Drift



Figure 8 Test Circuit of Temperature Drift

## Test result of Gain drift

| Dither $=100$, Chopper clock $=101$, Chopper ON , OSR = 111, ADC Clock=250KHz , VDD = 3V , VDDA = 2.4 Referance Voltage $=900 \mathrm{mV}$ |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: |
| Test Mode | $-20^{\circ} \mathrm{C} \sim 20^{\circ} \mathrm{C}$ | $0^{\circ} \mathrm{C} \sim 20^{\circ} \mathrm{C}$ | $40^{\circ} \mathrm{C} \sim 20^{\circ} \mathrm{C}$ | $60^{\circ} \mathrm{C} \sim 20^{\circ} \mathrm{C}$ |
|  | PPM/ ${ }^{\circ} \mathrm{C}$ |  |  |  |
| Gain = 1*1, Offset = 0 , AIN Buffer = Off, Ref Buffer = Off | -1.89 | 1.91 | -0.95 | -1.17 |
| Gain = 1*1, Offset =0, AIN Buffer = On, Ref Buffer = Off | -2.24 | -0.42 | -0.98 | -1.57 |
| Gain = 1*1, Offset =0, AIN Buffer = Off, Ref Buffer = On | 6.61 | 7.20 | -7.45 | -7.41 |
| Gain $=1 * 1$, Offset $=0$, AIN Buffer $=$ On, Ref Buffer $=$ On | 5.93 | 6.66 | -6.70 | -6.86 |
| Gain = 1*2, Offset =0, AIN Buffer = Off, Ref Buffer = Off | -1.55 | -1.30 | -1.15 | -0.49 |
| Gain = 1*2, Offset =0, AIN Buffer = On, Ref Buffer = Off | -1.43 | -1.18 | -1.10 | -0.66 |
| Gain $=1 * 2$, Offset $=0$, AIN Buffer $=$ Off, Ref Buffer $=$ On | 7.25 | 6.27 | -6.24 | -6.13 |
| Gain = 1*2, Offset =0, AIN Buffer = On, Ref Buffer = On | 6.76 | 6.85 | -7.21 | -6.51 |
| Gain = 1*4, Offset =0, AIN Buffer = Off, Ref Buffer = Off | -0.90 | -1.91 | -1.16 | -0.63 |
| Gain = 1*4, Offset =0, AIN Buffer = On, Ref Buffer = Off | -0.85 | -1.78 | -2.40 | -0.88 |
| Gain = 1*4, Offset = 0 , AIN Buffer = Off, Ref Buffer = On | 7.20 | 6.69 | -6.86 | -6.00 |
| Gain = 1*4, Offset =0, AIN Buffer = On, Ref Buffer = On | 7.33 | 7.12 | -7.45 | -6.24 |
| Gain $=1 * 16$, Offset $=0$ | -0.73 | -1.72 | -1.12 | -0.55 |
| Gain $=8 * 4$, Offset $=0$ | 1.66 | 3.10 | 0.25 | 0.12 |
| Gain $=8 * 16$, Offset $=0$ | 12.10 | 10.40 | -6.90 | -3.03 |
| Gain $=1 * 1$, Offset $=-1 / 4 \mathrm{Vref}$ | 1.32 | 0.82 | -2.74 | -2.83 |
| Gain $=1 * 2$, Offset $=-1 / 4 \mathrm{~V}$ ref | -0.81 | -0.59 | -0.87 | -0.94 |
| Gain $=1 * 4$, Offset $=-1 / 4 \mathrm{Vref}$ | -0.51 | -0.74 | -1.18 | -0.87 |
| Gain $=1 * 16$, Offset $=-1 / 4 \mathrm{Vref}$ | -0.10 | -0.55 | -1.19 | -1.19 |
| Gain $=8 * 4$, Offset $=-1 / 4 \mathrm{Vref}$ | 0.57 | 1.57 | -2.00 | -1.33 |
| Gain $=8 * 16$, Offset $=-1 / 4 \mathrm{~V}$ ref | 7.27 | 5.98 | 4.75 | -1.31 |

The maximum parameter of Gain temperature drift is $12 \mathrm{PPM} /{ }^{\circ} \mathrm{C}$. To realize a scale of 3rd class certification, $\pm 1.5$ Degree drift parameter under $-10^{\circ} \mathrm{C} \sim 40^{\circ} \mathrm{C}$ is equal to 20 PPM $/{ }^{\circ} \mathrm{C}$.

## Test result of OFFSET drift

| Dither $=100$, Chopper clock $=101$, Chopper ON , OSR $=111$, ADC Clock $=250 \mathrm{KHz}, \mathrm{VDD}=3 \mathrm{~V}, \mathrm{VDDA}=2.4$ |  |  |  |  |
| :---: | :---: | :---: | :---: | :---: |
| Mode | -20~20 | 0~20 | 40~20 | 60~20 |
|  | $\mathrm{nV} /{ }^{\circ} \mathrm{C}$ |  |  |  |
| Gain = 1*1, Offset = 0 , AIN Buffer = Off, Ref Buffer = Off | 714.96 | 539.08 | 980.58 | 581.00 |
| Gain = 1*1, Offset =0, AIN Buffer = On, Ref Buffer = Off | -2388.04 | -2204.52 | -2106.70 | -2333.95 |
| Gain = 1*1, Offset =0, AIN Buffer = Off, Ref Buffer = On | 645.31 | 475.93 | 740.56 | 525.74 |
| Gain = 1*1, Offset = , AIN Buffer = On, Ref Buffer = On | -2600.92 | -2770.58 | -2136.08 | -2269.00 |
| Gain = 1*2, Offset = , AIN Buffer = Off, Ref Buffer = Off | 255.90 | 207.35 | 477.90 | 827.18 |
| Gain = 1*2, Offset =0, AIN Buffer = On, Ref Buffer = Off | -2923.29 | -2914.77 | -2261.80 | -1938.61 |
| Gain = 1*2, Offset = 0 , AIN Buffer = Off, Ref Buffer = On | 249.03 | 168.16 | 434.16 | 744.57 |
| Gain = 1*2, Offset =0, AIN Buffer = On, Ref Buffer = On | -2816.38 | -2828.49 | -2352.39 | -2027.15 |
| Gain $=1 * 4$, Offset $=0$, AIN Buffer $=$ Off, Ref Buffer $=$ Off | 107.29 | 77.86 | 346.58 | 510.29 |
| Gain $=1 * 4$, Offset $=0$, AIN Buffer $=$ On, Ref Buffer = Off | -3097.09 | -2967.50 | -2487.59 | -2347.65 |
| Gain = 1*4, Offset = , AIN Buffer = Off, Ref Buffer = On | 121.11 | 39.05 | 349.34 | 476.37 |
| Gain = 1*4, Offset = , AIN Buffer = On, Ref Buffer = On | -3102.68 | -3026.86 | -2535.73 | -2322.09 |
| Gain $=1 * 16$, Offset $=0$ | -108.32 | -86.15 | -102.67 | -84.66 |
| Gain $=8 * 4$, Offset $=0$ | -16.00 | 1.58 | 13.07 | 28.88 |
| Gain $=8 * 16$, Offset $=0$ | -38.07 | -27.90 | -23.28 | -29.65 |
| Gain = 1*1, Offset $=-1 / 4 \mathrm{Vref}$ | 1542.99 | 1893.42 | 1861.54 | 1497.64 |
| Gain $=1 * 2$, Offset $=-1 / 4 \mathrm{~V}$ ref | 858.06 | 967.18 | 1115.57 | 1294.97 |
| Gain $=1 * 4$, Offset $=-1 / 4 \mathrm{Vref}$ | 480.44 | 568.10 | 574.48 | 715.75 |
| Gain $=1 * 16$, Offset $=-1 / 4$ Vref | -17.30 | 3.55 | -38.61 | -13.29 |
| Gain $=8 * 4$, Offset $=-1 / 4 \mathrm{Vref}$ | 32.75 | 60.18 | 49.19 | 60.29 |
| Gain $=8 * 16$, Offset $=-1 / 4 \mathrm{~V}$ ref | -21.29 | -9.80 | -23.14 | -21.91 |

If the input voltage of Load Cell is 3.3 V and output signal is $2 \mathrm{mV} / \mathrm{V}$, the maximum output voltage shall be 6.6 mV ( 3000 Count). According to the standard of 3rd-class scale, the maximum offset drift cannot over $\pm 1 \mathrm{e} / 5^{\circ} \mathrm{C}\left( \pm 0.2 \mathrm{e} /{ }^{\circ} \mathrm{C}\right)$, which is smaller than $440 \mathrm{nV} /{ }^{\circ} \mathrm{C}$. Under $-10^{\circ} \mathrm{C} \sim 40^{\circ} \mathrm{C}$ ambient temperature condition, the maximum Offset drift of HY11P13 when Gain=128 is $20 \mathrm{nV} /{ }^{\circ} \mathrm{C}$. Therefore, when choosing Load Cell, users must make sure the Gain drift is under $8 \sim 10 \mathrm{PPM} / /^{\circ} \mathrm{C}$ and Offset is lower than $400 \mathrm{nV} /{ }^{\circ} \mathrm{C}$ to conform to certified standard.

## 5. Conclusion

The maximum parameter of Gain temperature drift is $12 \mathrm{PPM} / /^{\circ} \mathrm{C}$. Realizing a scale of 3rd class certification, $\pm 1.5$ degree drift parameter under $-10^{\circ} \mathrm{C} \sim 40^{\circ} \mathrm{C}$ is equal to $20 \mathrm{PPM} /$ ${ }^{\circ} \mathrm{C}$. According to the standard of 3rd class certification, the parameter of offset cannot over $\pm 1 \mathrm{e} / 5^{\circ} \mathrm{C}\left( \pm 0.2 \mathrm{e} /^{\circ} \mathrm{C}\right)$ under $-10^{\circ} \mathrm{C} \sim 40^{\circ} \mathrm{C}$ ambient temperature condition.

| Standard of 3rd Class Certification | Chip : HY11P13 |
| :---: | :---: |
| Offset parameter $< \pm 1 \mathrm{e} / 5^{\circ} \mathrm{C}\left( \pm 0.2 \mathrm{e} / /^{\circ} \mathrm{C}\right)$ <br> Ambient temperature : $-10^{\circ} \mathrm{C} \sim 40^{\circ} \mathrm{C}$ | Application Condition: <br> 6 6mv ( 3000 Count) (Max. Output Voltage) <br> Ex: Load Cell inout Vollage 3.3V X Max. Output Voltage $2 m V / V=6.6 m V(3000 C O u n t)$ <br> Test Result : <br> Offset drift parameter about $20 \mathrm{nV} / /^{\circ} \mathrm{C}$ while Gain=128 <br> Conclusion: <br> <440nV $f^{\circ} \mathrm{C}$ |

## 6. Operation Description

### 6.1 Usage

### 6.1.1 Calibration Description

The program automatically enters into calibration mode if no calibration value exists in EEPROM. If there is a need to re-calibrate, click PT1.0 to turn the power on. After power on, let go PT1.0, ADC output code will be shown first in the calibration mode.


- Click PT1.0 to set the weight at full load (Max. Range of the measurement), key in the value on the blinking space. Click PT1.3 to ascend the value, from 0~9.
- Click PT1.0 to move right to the last space for going into zero point calibration procedure. At this point, it shows ADC output code, then re-click PT1.0 for saving zero value and go into next process.

- After finishing zero point calibration, next is to adjust standard weight calibration.

- Click PT1.3, value ascends, from 0 to 9 . Click PT1.0 to move right to the last space for going into standard weight calibration procedure. Put the
counterpoise as the standard weight criterion, and then re-click PT1.0 for saving calibration value, and goes into the next process.
- After standard weight calibration, go into the process of selecting resolution and decimal digits. Click PT1.3, the value ascends from 0 to 9 .
Click PT1.0 to move right to the last space and then re-click PT1.0 to save all value to EEPROM. Finally, get access into the weighing mode.



### 6.1.2 Weighing Description

Before weighing, it is necessary to have calibration value in EEPROM. If not, it is impossible to weigh. If re-calibration is in need, click PT1.0 $\rightarrow$ Zero or Tare Click PT1.0 $\rightarrow$ " Zero" or " Tare"

When the value is less than the one-tenth of the full load weight, PT1.0 is "Zero" function.

When the value is more than the one-tenth of the full load weight, PT1.0 is "Tare" function.

Click PT1.3 $\rightarrow$ switching display the ADC output code and weight value

### 6.1.3 Auto Zero

When the weight is within $\pm 1 / 4$ div of zero point range and it lasts for 1 second, Auto Zero will be started. If Auto Zero is more than one-tenth of the full load weight, this function is disabled.

